

# Electrical Impedance Tomography: Computation and Applications

Part 7: The Complete Electrode Model

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# From Measurements to a Forward Model

So far, we've discussed the voltage data  $V_{\text{meas}}$  that come from physical measurements, and also the continuum model.

Given a candidate conductivity, known electrode geometry and applied currents  $I$ , an electrode forward model predicts what the instrument would measure:

$$\sigma(x), I \xrightarrow{\text{forward model}} V_{\text{pred}}.$$

A realistic electrode forward model allows us to:

- support linearized and iterative reconstruction,
- generate synthetic data to test reconstruction algorithms and measurement strategies,
- connect ideal continuum data with finite electrode measurements.

# Common Boundary and Electrode Models

Different models retain different features of the physical electrodes:

| Model                    | Basic idealization                                                                                                   |
|--------------------------|----------------------------------------------------------------------------------------------------------------------|
| Continuum model          | Prescribe current density and measure voltage directly on the boundary; no discrete electrodes                       |
| Point electrode model    | Treat electrodes as points; ignore their finite size and contact impedance                                           |
| Gap model                | Use finite electrodes with uniform applied current density, but voltages doesn't need to be constant on an electrode |
| Shunt model              | Treat each finite electrode as a perfect conductor (so voltage is constant), but assume zero contact impedance       |
| Complete electrode model | Include finite, equipotential electrodes, redistribution of current, and nonzero contact impedance                   |

# Introducing the Complete Electrode Model

We will focus on the *Complete Electrode Model (CEM)*, which is widely regarded as the most accurate standard model for electrode-based EIT measurements.<sup>1</sup>

Simpler models are easier and cheaper to solve, but the CEM usually gives the most realistic description of practical low-frequency EIT measurements.

## What the CEM Predicts

Given the conductivity, electrode configuration, contact impedances, and applied electrode currents, the CEM predicts the resulting electrode voltages.

The model accounts for:

- the finite size and number of the electrodes,
- electrical contact between the electrodes and target,
- gaps between electrodes.

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<sup>1</sup>Somersalo, Cheney, and Isaacson, *SIAM J. Appl. Math.* 52 (1992), 1023–1040.

# How the CEM Models Applied Current

The CEM takes the *total* current delivered through each electrode as input:

$$I_\ell = \int_{e_\ell} \sigma \frac{\partial u}{\partial \mathbf{n}} ds.$$

It does not prescribe the current density separately at every point under the electrode.

- We assume the local current density may vary across the electrode.
- Due to conservation of charge, total electrode currents must satisfy

$$\sum_{\ell=1}^L I_\ell = 0.$$

- We assume no current crosses the boundary between electrodes:

$$\sigma \frac{\partial u}{\partial \mathbf{n}} = 0 \quad \text{on } \partial\Omega \setminus \bigcup_{\ell=1}^L e_\ell.$$

# Modeling Electrode Contact Imperfections

The voltage  $V_\ell$  of the metal electrode need not equal the tissue-side potential  $u(x)$  directly beneath it.

A thin contact layer (e.g. skin surface) creates an additional voltage drop.

Let  $z_\ell > 0$  denote the effective contact impedance of electrode  $e_\ell$ . The complete electrode model assumes

$$V_\ell - u = z_\ell \sigma \frac{\partial u}{\partial \mathbf{n}} \quad \text{on } e_\ell.$$

Equivalently,

$$u + z_\ell \sigma \frac{\partial u}{\partial \mathbf{n}} = V_\ell \quad \text{on } e_\ell.$$

If  $z_\ell = 0$ , this reduces to perfect electrical contact:  $u = V_\ell$  on the electrode.

# Units of the Contact Impedance

On electrode  $e_\ell$ , the CEM imposes

$$u + z_\ell j_n = U_\ell, \quad j_n = \sigma \frac{\partial u}{\partial \mathbf{n}}.$$

Since  $j_n$  is current per unit area,

$$[j_n] = \text{A/m}^2, \quad [z_\ell] = \frac{\text{V}}{\text{A/m}^2} = \boxed{\Omega \text{ m}^2}.$$

So the CEM parameter  $z_\ell$  is not the ordinary electrode impedance in ohms. For an electrode of area  $A_\ell$ , the corresponding scale is

$$R_{\text{contact}} \approx \frac{z_\ell}{A_\ell}.$$

For example, if  $A_\ell = 1 \text{ cm}^2$  and  $z_\ell = 10^{-2} \Omega \text{ m}^2$ , then  $R_{\text{contact}} \approx 100 \Omega$ .

In a 2D model, the out-of-plane height may be absorbed into the parameter, giving units of  $\Omega \text{ m}$  instead.

# Typical Contact-Impedance Scales

Values vary greatly with electrode material, skin preparation, and frequency. Some rough physical scales are:

| Contact                            | $z_\ell$ in $\Omega \text{ m}^2$ | $z_\ell/A_\ell$ for $1 \text{ cm}^2$ |
|------------------------------------|----------------------------------|--------------------------------------|
| Metal electrodes in a saline tank  | $10^{-4}$ – $10^{-2}$            | 1–100 $\Omega$                       |
| Well-prepared, gelled skin contact | $10^{-2}$ – $10^{-1}$            | 100 $\Omega$ –1 k $\Omega$           |
| Dry or poor skin contact           | $10^{-1}$ –1 or more             | 1–10 k $\Omega$ or more              |

## AC Measurements

Contact impedance generally depends on frequency and may be complex. At a fixed drive frequency, the basic CEM often uses an effective positive real value for  $z_\ell$ .

# The CEM Equations

Given the conductivity  $\sigma$ , contact impedances  $z_\ell$ , and balanced electrode currents  $I$ , solve for the interior potential  $u$  and electrode voltages  $V_{\text{pred}}$ :

$$\left\{ \begin{array}{ll} \nabla \cdot (\sigma \nabla u) = 0 & \text{in } \Omega, \\ \sigma \frac{\partial u}{\partial \mathbf{n}} = 0 & \text{between electrodes,} \\ u + z_\ell \sigma \frac{\partial u}{\partial \mathbf{n}} = V_\ell & \text{on } e_\ell, \\ \int_{e_\ell} \sigma \frac{\partial u}{\partial \mathbf{n}} ds = I_\ell, & \ell = 1, \dots, L, \\ \sum_{\ell=1}^L V_\ell = 0 & \text{(reference choice).} \end{array} \right.$$

This is the “gold standard” model used in most EIT simulation and reconstruction

Next, we will examine a model-based reconstruction method that uses the CEM in the forward-modeling step.